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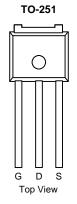
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STU12N65M5-VB Datasheet

N-Channel 700V (D-S)Super Junction Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V) at T _J max.	700			
R _{DS(on)} at 25 °C (Ω)	V _{GS} = 10 V 0.45			
Q _g max. (nC)	70			
Q _{gs} (nC)	9			
Q _{gd} (nC)	16			
Configuration	Single			

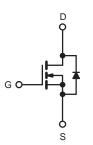


FEATURES

- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- · Reduced switching and conduction losses
- Ultra low gate charge (Qg)
- Avalanche energy rated (UIS)

APPLICATIONS

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T_C	= 25 °C, unl	ess otherwis	se noted)		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V_{DS}	700	
Gate-Source Voltage			V_{GS}	± 30	V
Continuous Prain Courset /T 150 °C\	V _{GS} at 10 V	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$	- I _D	11	
Continuous Drain Current (T _J = 150 °C)		T _C = 100 °C		8	Α
Pulsed Drain Current ^a			I _{DM}	28	
Linear Derating Factor				1.4	W/°C
Single Pulse Avalanche Energy b			E _{AS}	226	mJ
Maximum Power Dissipation			P_{D}	156	W
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C
Drain-Source Voltage Slope	ope T _J = 125 °C		-15.77-11	37	1//22
Reverse Diode dV/dt d			dV/dt	28	V/ns
Soldering Recommendations (Peak Temperature) c for 10 s			300	°C	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature.
- b. V_{DD} = 50 V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 4 A.
- c. 1.6 mm from case.
- d. $I_{SD} \le I_D$, dI/dt = 100 A/ μ s, starting $T_J = 25$ °C.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	62	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.8	G/ VV	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		-					
Drain-Source Breakdown Voltage	V_{DS}	V _{GS} :	= 0 V, I _D = 250 μA	700	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.78	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	2	-	4	V
		V _{GS} = ± 20 V		-	-	± 100	nA
Gate-Source Leakage	I_{GSS}		V _{GS} = ± 30 V	-	_	± 1	μA
			= 700 V, V _{GS} = 0 V	-	-	1	
Zero Gate Voltage Drain Current	I_{DSS}		/, V _{GS} = 0 V, T _J = 125 °C	-	_	10	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V		-	0.45	-	Ω
Forward Transconductance	9fs	V _{DS}	s = 30 V, I _D = 6 A	-	3.5	-	S
Dynamic		1			·		
Input Capacitance	C _{iss}		V _{GS} = 0 V,	-	1224	-	
Output Capacitance	Coss	7	$V_{DS} = 100 \text{ V},$	-	65	-	
Reverse Transfer Capacitance	C _{rss}	f = 1 MHz		-	4	-	pF
Effective Output Capacitance, Energy Related ^a	C _{o(er)}	V _{DS} = 0 V to 520 V, V _{GS} = 0 V		-	50	-	
Effective Output Capacitance, Time Related ^b	C _{o(tr)}			-	160	-	
Total Gate Charge	Qg			-	35	70	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$V_{GS} = 10 \text{ V}$ $I_{D} = 6 \text{ A}, V_{DS} = 520 \text{ V}$		9	-	nC
Gate-Drain Charge	Q _{gd}	1 1 1		-	16	-	
Turn-On Delay Time	t _{d(on)}	V _{DD} = 520 V, I _D = 6 A,		-	16	32	
Rise Time	t _r			-	19	38	no
Turn-Off Delay Time	t _{d(off)}		$V_{GS} = 320 \text{ V}, R_g = 9.1 \Omega$		35	70	ns
Fall Time	t _f				18	36	
Gate Input Resistance	R_g	f = 1 MHz, open drain		-	0.81	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	11	_
Pulsed Diode Forward Current	I _{SM}			-	-	28	A
Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 6 A, V _{GS} = 0 V		-	1.0	1.2	V
Reverse Recovery Time	t _{rr}	T _J = 25 °C, $I_F = I_S = 6$ A, dl/dt = 100 A/ μ s, $V_R = 25$ V		-	309	618	ns
Reverse Recovery Charge	Q _{rr}			-	3.8	7.6	μC
Reverse Recovery Current	I _{RRM}				21	_	A

Notes

- a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

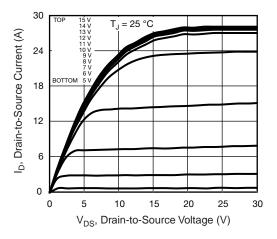


Fig. 1 - Typical Output Characteristics

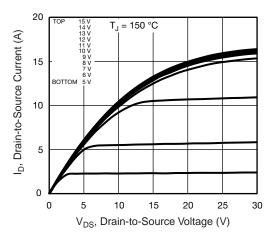


Fig. 2 - Typical Output Characteristics

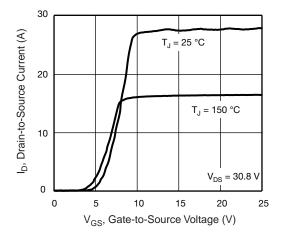


Fig. 3 - Typical Transfer Characteristics

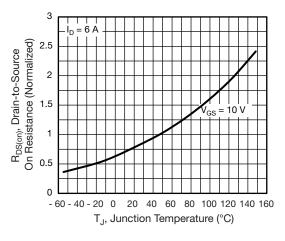


Fig. 4 - Normalized On-Resistance vs. Temperature

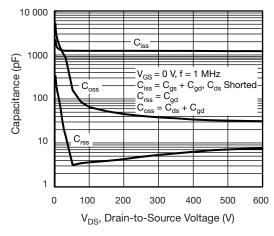


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

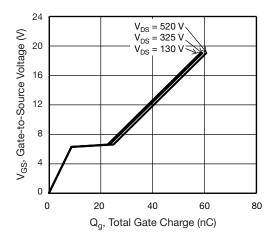


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



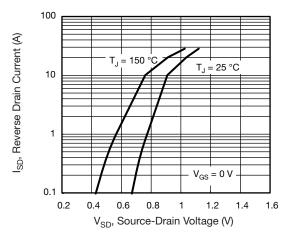


Fig. 7 - Typical Source-Drain Diode Forward Voltage

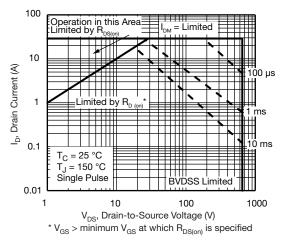


Fig. 8 - Maximum Safe Operating Area

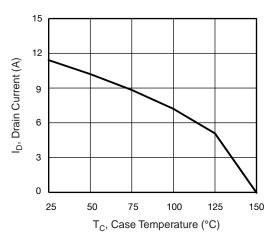


Fig. 9 - Maximum Drain Current vs. Case Temperature

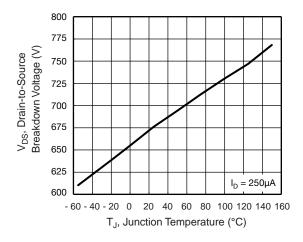


Fig. 10 - Temperature vs. Drain-to-Source Voltage

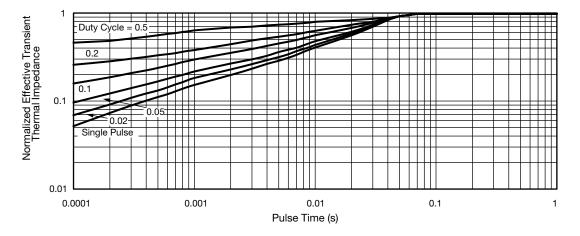


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



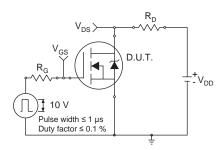


Fig. 12 - Switching Time Test Circuit

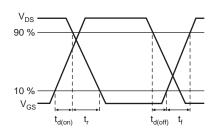


Fig. 13 - Switching Time Waveforms

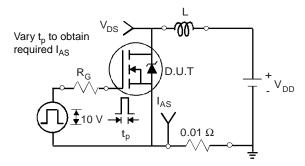


Fig. 14 - Unclamped Inductive Test Circuit

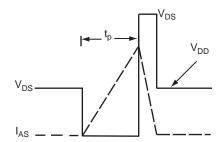


Fig. 15 - Unclamped Inductive Waveforms

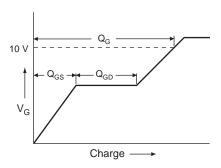


Fig. 16 - Basic Gate Charge Waveform

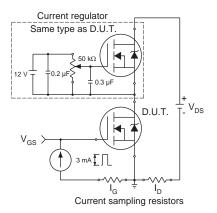
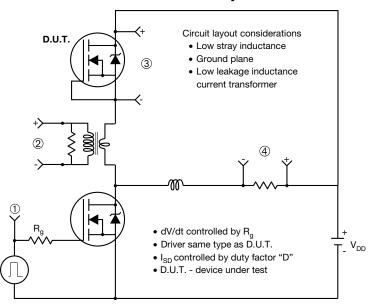


Fig. 17 - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



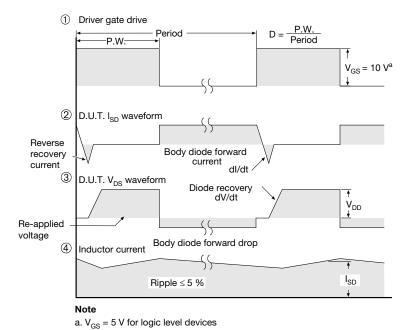
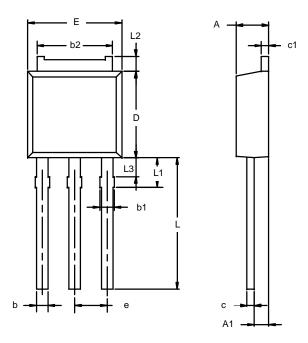


Fig. 18 - For N-Channel



TO-251AA



Note:	Dimension	L3 is for	reference	only.
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	MILLIMETERS		INCHES		
Dim	Min	Max	Min	Max	
Α	2.21	2.38	0.087	0.094	
A1	0.89	1.14	0.035	0.045	
b	0.71	0.89	0.028	0.035	
b1	0.76	1.14	0.030	0.045	
b2	5.23	5.43	0.206	0.214	
С	0.46	0.58	0.018	0.023	
с1	0.46	0.58	0.018	0.023	
D	5.97	6.22	0.235	0.245	
Е	6.48	6.73	0.255	0.265	
е	2.28	BSC	0.090	BSC	
L	3.89	9.53	0.153	0.375	
L1	1.91	2.28	0.075	0.090	
L2	0.89	1.27	0.035	0.050	
L3	1.15	1.52	0.045	0.060	

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